Schedule of Accreditation

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United Kingdom Accreditation Service

2 Pine Trees, Chertsey Lane, Staines-upon-Thames, TW18 3HR, UK

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Accredited to ISO/IEC 17025:2017

Proserv UK Limited

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Calibration performed at the above address only

CALIBRATION AND MEASUREMENT CAPABILITY (CMC)

Measured Quantity Instrument or Gauge	Range	Expanded Measurement Uncertainty (k = 2)	Remarks
ELECTRICAL			
DC RESISTANCE			
Measurement	0 mΩ to 100 mΩ 100 mΩ to 1 Ω 1 Ω to 10 Ω 10 Ω to 100 Ω 100 Ω to 1 kΩ 1 kΩ to 10 kΩ 10 kΩ to 100 kΩ 100 kΩ to 1 MΩ 1 MΩ to 10 MΩ 10 MΩ to 100 MΩ 100 MΩ to 1 GΩ	Q[120 μΩ/Ω, 21 μΩ] Q[69 μΩ/Ω, 18 μΩ] Q[46 μΩ/Ω, 120 μΩ] Q[35 μΩ/Ω, 0.97 mΩ] Q[35 μΩ/Ω, 9.5 mΩ] Q[35 μΩ/Ω, 95 mΩ] Q[52 μΩ/Ω, 1.00 Ω] Q[110 μΩ/Ω, 13 Ω] Q[180 μΩ/Ω, 190 Ω] Q[0.12 %, 12 kΩ] Q[0.87 %, 1.2 MΩ]	Measurement of DC resistance values using 2-wire or 4-wire configurations, as appropriate.
Generation	0 Ω to 10 Ω 10 Ω to 100 Ω 100 Ω to 1 k Ω 1 kΩ to 10 kΩ 10 kΩ to 100 kΩ 100 kΩ to 1 MΩ 1 MΩ to 10 MΩ 10 MΩ to 100 MΩ 100 MΩ to 1 GΩ	Q[120 μΩ/Ω, 5.8 mΩ] Q[58 μΩ/Ω, 5.8 mΩ] Q[46 μΩ/Ω, 46 mΩ] Q[46 μΩ/Ω, 470 mΩ] Q[46 μΩ/Ω, 4.7 Ω] Q[120 μΩ/Ω, 48 Ω] Q[400 μΩ/Ω, 490 Ω] Q[0.58 %, 6.4 kΩ] Q[1.2 %, 400 kΩ]	Known DC resistance values for application to resistance measuring instruments.
DC VOLTAGE			
Measurement	0 mV to 10 mV 10 mV to 100 mV 100 mV to 300 mV 300 mV to 1 V 1 V to 10 V 10 V to 100 V 100 V to 1 kV	Q[35 μV/V, 4.4 μV] Q[35 μV/V, 5.5 μV] Q[35 μV/V, 12 μV] Q[21 μV/V, 16 μV] Q[21 μV/V, 150 μV] Q[35 μV/V, 1.8 mV] Q[35 μV/V, 19 mV]	Measurement of DC voltages provided by power supplies, calibrators and similar instruments.
Generation	0 mV to 200 mV 200 mV to 2 V 2 V to 20 V 20 V to 200 V 200 V to 1020 V	Q[35 μV/V, 4.3 μV] Q[35 μV/V, 9.1μV] Q[29 μV/V, 81 μV] Q[35 μV/V, 110 mV] Q[35 μV/V, 810 mV]	Known DC voltages for application to voltage measuring instruments.

Measured Quantity Instrument or Gauge	Range	Expanded Measurement Uncertainty (k = 2)	Remarks
ELECTRICAL (continued)			
DC CURRENT			
Measurement	0 µA to 10 µA 10 µA to 100 µA 100 µA to 1 mA 1 mA to 10 mA 10 mA to 100 mA 100 mA to 1 A 1 A to 10 A	Q[240µA/A, 15 nA] Q[120 µA/A, 24 nA] Q[120 µA/A, 97 nA] Q[120 µA/A, 1.4 µA] Q[120 µA/A, 8.3 µA] Q[240 µA/A, 200 µA] Q[0.09 %, 3.9 mA]	Measurement of DC currents provided by power supplies, calibrators and similar instruments.
Simulation with multi turn coil and measurement with current clamp	0 A to 60 A 60 A to 300 A 300 A to 1.5 kA	0.42 % + 240 mA 0.48 % + 240 mA 0.30 % + 240 mA	2 turn coil 10 turn coil 50 turn coil
Generation	0 µA to 200 µA 200 µA to 2 mA 2 mA to 20 mA 20 mA to 200 mA 200 mA to 2 A 2 A to 30 A	Q[120 µA/A, 35 nA] Q[92 µA/A, 57 nA] Q[58 µA/A, 430 nA] Q[92 µA/A, 4.5 µA] Q[170 µA/A, 110 µA] Q[460 µA/A, 24 mA]	Known DC currents for application to current measuring instruments.
AC RESISTANCE *at 50 Hz*	0.05 Ω to 10 Ω 10 Ω to 100 Ω 100 Ω to 1 kΩ	Q[0.58 %, 7.6 mΩ] Q[0.58 %, 19 mΩ] Q[0.58 %, 35 mΩ]	Known AC Resistance values for the calibration of earth bond testers and loop impedance testers.
AC VOLTAGE			
Measurement	*40 Hz to 200 Hz* 0 mV to 30 mV 30 mV to 300 mV 300 mV to 3 V 3 V to 30 V 30 V to 300 V *40 Hz to 100 Hz* 300 V to 1 kV	 Q[0.070 %, 80 µV] Q[0.070 %, 230 µV] Q[0.070 %, 4.9 mV] Q[0.070 %, 49 mV] Q[0.23 %, 200 mV] Q[0.23 %, 1.6 V]	Measurement of AC voltages provided by power supplies, calibrators and similar instruments.
Generation	*10 Hz to 44 Hz* 0 mV to 200 mV 200 mV to 2 V 2 V to 20 V *30 Hz to 44 Hz* 20 V to 200 V *44 Hz to 1 kHz* 0 mV to 200 mV 200 mV to 2 V 2 V to 20 V 20 V to 200 V 200 V to 700 V	 Q[0.23 %, 87 µV] Q[0.23 %, 0.74 mV] Q[0.23 %, 8.3 mV] Q[0.069 %, 130 mV] Q[460 µV/V, 48 µV] Q[460 µV/V, 420 µV] Q[400 µV/V, 7.0 mV] Q[460 µV/V, 120 mV] Q[460 µV/V, 370 mV]	Known AC voltages for application to voltage measuring instruments. 44 Hz minimum frequency on the 2 V to 20 V range.

Measured Quantity Instrument or Gauge	Range	Expanded Measurement Uncertainty (k = 2)	Remarks
ELECTRICAL (continued)			
AC VOLTAGE (continued)			
Generation (continued)	*1 kHz to 20 kHz* 0 mV to 200 mV 200 mV to 2 V 2 V to 20 V 20 V to 200 V *1 kHz to 10 kHz* 200 V to 700 V	 Q[0.10 %, 220 µV] Q[0.10 %, 2.2 mV] Q[0.081 %, 20 mV] Q[0.10 %, 310 mV] Q[0.17 %, 700 mV]	
AC CURRENT			
Measurement	*40 Hz to 60 Hz* 0 µA to 300 µA 300 µA to 3 mA 3 mA to 30 mA 30 mA to 300 mA 300 mA to 3 A 3 A to 10 A	 Q[0.23 %, 0.80 µA] Q[0.23 %, 5.0 µA] Q[0.23 %, 52 µA] Q[0.23 %, 0.51 mA] Q[0.23 %, 2.1mA] Q[0.23 %, 29 mA]	Measurement of AC currents provided by power supplies, calibrators and similar instruments.
Simulation with multi turn coil and measurement with current clamp.	30 Hz to 60 Hz 0.5 A to 60 A 60 A to 300 A 300 A to 1.5 kA	 0.42 % + 240 mA 0.48 % + 240 mA 0.30 % + 240 mA	 2 turn coil 10 turn coil 50 turn coil
Generation	*40 Hz to 1 kHz* 25 µA to 200 µA 200 µA to 2 mA 2 mA to 20 mA 20 mA to 200 mA 200 mA to 2 A 2 A to 30 A	 Q[0.12 %, 0.30 µA] Q[0.10 %, 1.1 µA] Q[0.10 %, 7.7 µA] Q[0.10 %, 72 µA] Q[0.44 %, 0.70 mA] Q[0.40 %, 58 mA]	Known AC currents for application to current measuring instruments.
CAPACITANCE			
Generation	*At 1 kHz:* 1 nF 10 nF 20 nF 50 nF 100 nF 1 µF 10 µF	 0.026 nF 0.060 nF 0.10 nF 0.25 nF 0.39 nF 0.028 µF 0.10 µF	Fixed values of capacitance for the calibration of capacitance meters and similar instruments.
FREQUENCY			
Generation	1 Hz to 100 Hz 100 Hz to 1 kHz 1 kHz to 20 kHz 20 kHz to 100 kHz 100 kHz to 10 MHz	Q[23 µHz/Hz, 0.020 mHz] Q[23 µHz/Hz, 0.20 mHz] Q[23 µHz/Hz, 4.0 mHz] Q[23 µHz/Hz, 20 mHz] Q[23 µHz/Hz, 2.0 Hz]	Generation of known frequencies for application to frequency measuring instruments.
Measurement	1 Hz to 100 kHz	Q[14 µHz/Hz, 2.6 Hz]	Using frequency meter.

Measured Quantity Instrument or Gauge	Range	Expanded Measurement Uncertainty (k = 2)	Remarks
17th Edition Equipment			Calibrations to support equipment designed for testing to the IET Requirements for Electrical Installations (BS 7671:2008, Amds 1,2 and 3)
Line Voltage	*At 50 Hz:* 240 V to 250 V	Q[0.23 %, 1.2 V]	
Output Voltage	*At 50 Hz:* 100 V to 400 V	Q[0.20 %, 1.2 V]	
Continuity Current	0 mA to 300 mA	Q[2.6 %, 0.80 mA]	
Continuity Resistance	0.1 Ω to 20 Ω 100 Ω 1 kΩ	Q[1.2 %, 30 mΩ] Q[1.2 %, 30 mΩ] Q[1.2 %, 34 mΩ]	
Insulation Resistance	0 Ω to 20 kΩ 20 kΩ to 100 kΩ 100 kΩ to 600 kΩ 600 kΩ to 1 MΩ 1 MΩ to 5 MΩ 5 MΩ to 100 MΩ 100 MΩ to 600 MΩ 600 MΩ to 1 GΩ	Q[0.35 %, 0.61 Ω] Q[0.35 %, 2.1 Ω] Q[0.35 %, 14 Ω] Q[0.35 %, 23 Ω] Q[0.35%, 0.43 kΩ] Q[3.5 %, 64 kΩ] Q[3.5 %, 4.9 MΩ] Q[3.5 %, 8.1 MΩ]	
Insulation Test Voltage	50 V to 1 kV	Q[1.2 %, 1.5 V]	
Loop Resistance	0.06 Ω 0.11 Ω 0.22 Ω 0.33 Ω 0.5 Ω 1 Ω 5 Ω 10 Ω 100 Ω 1 kΩ	Q[0.60 %, 4.7 mΩ] Q[0.60 %, 4.7 mΩ] Q[0.60 %, 4.8 mΩ] Q[0.60 %, 4.8 mΩ] Q[0.60 %, 4.8 mΩ] Q[0.60 %, 4.9 mΩ] Q[0.60 %, 4.9 mΩ] Q[0.60 %, 7.6 mΩ] Q[0.60 %, 19 mΩ] Q[0.60 %, 35 mΩ]	
PAT Earth Bond Current	0 mA to 100mA 0.1 A to 10 A 10 A to 20 A	Q[1.7 %, 7.1 mA] Q[1.7 %, 18 mA] Q[1.7 %, 24 mA]	
PAT Earth Bond Resistance	0 Ω to 10 Ω 10 Ω to 100 Ω 100 Ω to 1 kΩ	Q[0.58 %, 7.6 mΩ] Q[0.58 %, 19 mΩ] Q[0.58 %, 35 mΩ]	

Measured Quantity Instrument or Gauge	Range	Expanded Measurement Uncertainty (k = 2)	Remarks
17th Edition Equipment (continued)			
PAT Insulation Resistance	See *Insulation resistance* on previous page.	See *Insulation resistance* on previous page.	
PAT Leakage Current	240 µA to 7.7 mA	Q[1.7 %, 9.6 µA]	
PAT Load Test	At 0.13 kVA	Q[5.8 %, 120 mΩ]	
RCD Current	0 mA to 300 mA *0 ms to 190 ms* 0 mA to 300mA *190 ms to 5 s* 300 mA-2 A *0 ms to 190 ms* 300 mA to 2 A *190 ms to 5 s*	 Q[5.8 %, 840 µA] Q[1.4 %, 840 µA] Q[5.8 %, 3.0 mA] Q[1.4 %, 3.0 mA]	
RCD Time	20ms to 390ms 900ms	5.9 ms 10 ms	
ELECTRICAL SIMULATION OF TEMPERATURE			
Thermocouple capabilities listed below are given for type T and k Base, using EMF sensitivity values as listed in BS EN 60584-1:2013. Other Thermocouple types can be calibrated, the uncertainties will correspond to the appropriate sensitivities listed. Calibrations which include the internal reference junction (CJC) are available for types: J, K, N, T, E, R, S, B & C			
Measurement internal reference junction enabled			
Type K	-200 ˚C to 1350 ˚C	0.40 ˚C	
Type T	-200˚C to 400˚C	0.35 ˚C	
Simulation internal reference junction enabled			
Type K	-200 ˚C to 1350 ˚C	0.40 ˚C	
Type T	-200˚C to 400˚C	0.35 ˚C	
Resistance thermometer Measurement	-190 °C to 0 °C 0 °C to 100 °C 100 °C to 400 °C 400 °C to 830 °C	0.28 °C 0.12 °C 0.13 °C 0.14 °C	
Resistance thermometer Simulation	-190 °C to 830 °C	0.28 °C	

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Measured Quantity Instrument or Gauge	Range	Expanded Measurement Uncertainty (k = 2)	Remarks
PRESSURE			Methods consistent with EURAMET CG17.
Gas Pressure (gauge)			
Calibration of pressure indicating instruments and gauges	-90 kPa to 0 kPa 0 kPa to 3 MPa 3 MPa to 14 MPa	Q[0.0020 %, 4.0 Pa] Q[0.0036 %, 2.7 kPa] Q[0.0020 %, 0.50 kPa]	Calibration of pressure transmitters and transducers with an electrical output may be undertaken.
Hydraulic Pressure (gauge)			
Calibration of pressure indicating instruments and gauges	0 kPa to 690 kPa 690 kPa to 6.9 MPa 6.9 MPa to 139 MPa 120 MPa to 413 MPa	Q[0.0082 %, 1.2 kPa] Q[0.010 %, 3.3 kPa] Q[0.020 %, 40 kPa] Q[0.020 %, 41 kPa]	Absolute pressures across these ranges can be generated which will attract an additional 600 Pa uncertainty.
END			

Appendix - Calibration and Measurement Capabilities

Introduction

The definitive statement of the accreditation status of a calibration laboratory is the Accreditation Certificate and the associated Schedule of Accreditation. This Schedule of Accreditation is a critical document, as it defines the measurement capabilities, ranges and boundaries of the calibration activities for which the organisation holds accreditation.

Calibration and Measurement Capabilities (CMCs)

The capabilities provided by accredited calibration laboratories are described by the Calibration and Measurement Capability (CMC), which expresses the lowest measurement uncertainty that can be achieved during a calibration. If a particular device under calibration itself contributes significantly to the uncertainty (for example, if it has limited resolution or exhibits significant non-repeatability) then the uncertainty quoted on a calibration certificate will be increased to account for such factors.

The CMC is normally used to describe the uncertainty that appears in an accredited calibration laboratory's schedule of accreditation and is the uncertainty for which the laboratory has been accredited using the procedure that was the subject of assessment. The measurement uncertainty is calculated according to the procedures given in the GUM and is normally stated as an expanded uncertainty at a coverage probability of 95 %, which usually requires the use of a coverage factor of $k = 2$. An accredited laboratory is not permitted to quote an uncertainty that is smaller than the published measurement uncertainty in certificates issued under its accreditation.

Expression of CMCs - symbols and units

It should be noted that the percentage symbol (%) represents the number 0.01. In cases where the measurement uncertainty is stated as a percentage, this is to be interpreted as meaning percentage of the measurand.
Thus, for example, a measurement uncertainty of 1.5 % means $1.5 \times 0.01 \times q$, where q is the quantity value.

The notation Q[a, b] stands for the root-sum-square of the terms between brackets: $Q[a, b] = [a^2 + b^2]^{1/2}$